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APPLICATION NO. FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/647,472 08/26/2003	Lawrence M. Burns	1875.3770001	2309
26111 7590 01/12/2006	EXAM	EXAMINER	
STERNE, KESSLER, GOLDSTE	NGUYEN	NGUYEN, JIMMY	
1100 NEW YORK AVENUE, N.W.			
WASHINGTON, DC 20005		ART UNIT	PAPER NUMBER
·		2829	

DATE MAILED: 01/12/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

A	1	(

	Application No.	Applicant(s)				
	10/647,472	BURNS ET AL.				
Office Action Summary	Examiner	Art Unit				
	Jimmy Nguyen	2829				
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address				
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	i6(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days ill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONEI	nely filed s will be considered timely. the mailing date of this communication. D (35 U.S.C. § 133).				
Status						
1)⊠ Responsive to communication(s) filed on 01 No	ovember 2005.					
•—						
3) Since this application is in condition for allowar	ice except for formal matters, pro	secution as to the merits is				
closed in accordance with the practice under E	x parte Quayle, 1935 C.D. 11, 45	53 O.G. 213.				
Disposition of Claims						
4)⊠ Claim(s) <u>1-20</u> is/are pending in the application.						
4a) Of the above claim(s) is/are withdrawn from consideration.						
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>1 - 20</u> is/are rejected.						
7) Claim(s) is/are objected to.						
8) Claim(s) are subject to restriction and/or	r election requirement.					
Application Papers						
9) The specification is objected to by the Examine	r.					
10)⊠ The drawing(s) filed on <u>26 August 2003</u> is/are:	a)⊠ accepted or b)□ objected	to by the Examiner.				
Applicant may not request that any objection to the	drawing(s) be held in abeyance. See	e 37 CFR 1.85(a).				
Replacement drawing sheet(s) including the correct						
11)☐ The oath or declaration is objected to by the Ex	aminer. Note the attached Office	Action or form PTO-152.				
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priority documents application from the International Bureau	s have been received. s have been received in Applicati ity documents have been receive i (PCT Rule 17.2(a)).	on No ed in this National Stage				
* See the attached detailed Office action for a list Attachment(s)	or the certified copies not receive	ea.				
1) Notice of References Cited (PTO-892)	4) Interview Summary					
2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date 1105.	Paper No(s)/Mail Da					

DETAILED ACTION

Response to Argument

The examiner acknowledges the amendment filed 10/11/05 has been carefully considered and upon further search the examiner is hereby make a new ground of rejection.

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

2. Claims 1 - 4,11 – 14 are rejected under 35 U.S.C. 102(e) as being anticipated Kiribata et al (US 5,764,655).

As to claims 1,11,14, Kiribata et al discloses (figs 1,2) a method and system of monitoring an integrated circuit chip, comprising:

(a) receiving at least one digitized sense signal (signal from IC to tester) from the integrated circuit chip (1, 2), whereby the at least one digitized sense signal represents a corresponding process-dependent parameter (performance parameters, column 2 line 55 - 60) within the integrated circuit chip (1,2); and

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(b) determining an analog value (the parameters could be digital or analog form) for the at least one process dependent circuit parameters (performance parameters) from the corresponding at least one digitized signal; wherein the process-dependent parameter (performance parameters) is measured within a process monitor portion of the integrated circuit (1,2) and the at least one determined analog value is utilized (performance parameters) to correct for the process-dependent parameter in an operational portion of the integrated circuit.

As to claims 3, 13, Kiribata et al discloses (figs 1,2) the method according to claim 1, wherein step (b) comprises retrieving the at least one value (expected value, from the tester) from a look-up table using the at least one digitized signal.

As to claims 4, 14, Kiribata et al discloses (figs 1,2) the method according to claim 1, wherein step (b) comprises calculating (from tester) the at least one value from the at least one digitized signal.

As to claims 2, 12, Kiribata et al discloses (figs 1,2) a method wherein steps (a) and (b) are perform outside of the ic (1, 2) (it been performed from the tester).

Claim Rejections - 35 USC § 103

2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

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3. Claims 5 – 10, 15 – 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kiribata et al (US 5,764,655).

As to claims 5 – 10, 15 –20, Kiribata et al disclosed the tester sensed the performance parameters of the IC chips (1, 2). However, the performance parameters are the broad terms of the following parameters

a gate-to-source threshold voltage of a transistor fabricated on the integrated circuit chip;

a transconductance parameter of a transistor fabricated on integrated circuit chip;

a sheet resistance of a resistor fabricated on the integrated circuit chip;

a temperature of the integrated circuit chip; and

a power supply voltage on the integrated circuit chip.

It would have been obvious to one having an ordinary skill in the art at the time of the invention was made to included the parameters such as (temperature, powers supply, sheet resistance and transconductance) for the purpose of recognizing the things that effect the operation of chip to improve, correct, and detect fault

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Conclusion

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Jimmy Nguyen whose telephone number is 571 -272-

1965. The examiner can normally be reached on M-f from 9 to 5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Ramtez Nestor, can be reached on 571-272-2034. The fax phone number

for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the

Patent Application Information Retrieval (PAIR) system. Status information for

published applications may be obtained from either Private PAIR or Public PAIR.

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For more information about the PAIR system, see http://pair-direct.uspto.gov. Should

you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

JN.

1/6/2006

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